

Thursday 30 <sup>th</sup> June							
9:00	<b>Welcome and Plenary Lectures (GHD Auditorium 49-200)</b>						
9:10	<b>Prof. Roger Wepf</b> <i>Electron microscopy</i>						
9:50	<b>Dr. Leonie van't Hag</b> <i>Neutron scattering studies on protein-lipid interactions for evolving biological, biomedical and food technology applications</i>						
10:30	Coffee break						
11:00	<b>Prof. Erica Wanless</b> <i>How does neutron reflectometry aid our understanding of polymer brush coatings?</i>						
11:40	<b>Dr. Craig Stoppiello</b> <i>X-ray characterisation of carbon nanomaterials</i>						
12:10	Lunch						
	Concurrent 1	Concurrent 2	Concurrent 3	Concurrent 4	Concurrent 5	Concurrent 6	Concurrent 7
	Lab sessions				Workshops		
13:00	Session 1 Electron microscopy (SEM/TEM)	Particle characterisation (particle sizing, particle imaging)	X-ray analysis (XPS, SAXS, reflectometry)	CryoTEM	Surface analysis (XPS/TOF-SIMS)	Bulk scattering (SAXS, SANS, USANS)	Interfacial layer characterisation (reflectometry/GISAXS/IRM)
					50-S201	46-230	46-371
15:00	Coffee break						
	Concurrent 1	Concurrent 2	Concurrent 3	Concurrent 4	Concurrent 5	Concurrent 6	Concurrent 7
	Lab sessions				Workshops		
15:30	Session 2 Electron microscopy (SEM/TEM)	Particle characterisation (particle sizing, particle imaging)	X-ray analysis (XPS, SAXS, reflectometry)	CryoTEM	Surface analysis (XPS/TOF-SIMS)	Bulk scattering (SAXS, SANS, USANS)	Interfacial layer characterisation (reflectometry/GISAXS/IRM)
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17:30	Break						
18:00	BBQ dinner – St Leo's College						

Friday 1 <sup>st</sup> July							
	Concurrent 1	Concurrent 2	Concurrent 3	Concurrent 4	Concurrent 5	Concurrent 6	
9:00	Lab sessions				Workshops		
Session 3	Electron microscopy (SEM/TEM)	Particle characterisation (particle sizing, particle imaging)	CryoTEM	XPS background and fundamentals	SAS data modelling	Data reduction for reflectometry, GISAXS and ellipsometry	
				50-S201	46-230	46-371	
11:00	Coffee break						
	Concurrent 1	Concurrent 2	Concurrent 3	Concurrent 4	Concurrent 5	Concurrent 6	
11:30	Lab sessions				Workshops		
Session 4	Electron microscopy (SEM/TEM)	Particle characterisation (particle sizing, particle imaging)	CryoTEM	XPS data processing and analysis	SAS data reduction and processing	Data analysis for reflectometry, GISAXS and ellipsometry	
				50-S201	46-230	46-371	
				Workshops			SAS data analysis in XSACT - presented by Xenocs
13:30	End of workshop						